



nanoParset

Fastest, most flexible tester in the world

Application

- Final Test up to 6 or 12 pins
- Multi-site Wafer Testing

Key Feature

- Maximum supply and current per channel 400V/3A
- Handler and prober agnostic
- Near-zero footprint
- Extreme short test times, increasing UPH
- Extreme flexibility
- Configuration:
 - 1 booster controller (nTHBC)
 - Up to 4 test heads (nSBTH) with 6 channels connected to 2 handlers
- Fast Kelvin check without switching relays
- Ultra-fast leakage test
- Pin Electronics
- Multi-site testing
- Optional SEMI standard with SECS/GEM interface